

Royal Microscopical Society



First Announcement, Two One-Day Workshops, Apr 2011:

3rd Meeting **ADVANCED TEM & TOM**

Aberration Corrected & Quantitative (S)TEM (Mon 11 Apr 2011)

Scope and Content:

- Aberration Correction in TEM/ STEM
- Monochromation and Energy filters
- In-Situ TEM, Dynamic TEM
- Atomic resolution TEM
- Quantitative Image Interpretation

Advances in Tomography III (Tue 12 Apr 2011)

Scope and Content:

- Biological (TEM, light microscope)
- Materials (TEM, SEM, FIB, X-rays)
- Multidisciplinary Tomography
- Novel Optical & Diffraction Tomography
- Reconstruction algorithms

Invited Speakers:

- Angus Kirkland, Oxford
 - Max Haider, CEOS, Heidelberg
 - Jun Yuan, York
 - Lothar Houben, Juelich
 - David Bell, Harvard (t.b.c.)
 - Ian Ross/Th Walther, Sheffield
 - Phil Withers, Manchester
 - Sara Bals, Antwerp
 - Christian Schroer, Dresden
 - Heiner Friedrich, Utrecht
 - Tobias Starborg, Manchester
- (further names to be confirmed)

Contributed papers (oral or posters) are warmly welcomed and will form an essential part of the meetings.

Registration information can be found on:

[http:// www.rms.org.uk/events/forthcoming_events](http://www.rms.org.uk/events/forthcoming_events)

Venue: ***University of Sheffield, Mappin Hall***

Organising Team: *Günter Möbus (Materials), Paul Verkade (Biology)*
Sponsors: to be confirmed